

Search Notes

Application/Control No.

10/762,453

Examiner

David E. Martinez

Applicant(s)/Patent under
Reexamination

CHANG, AN-SHENG

Art Unit

2181

SEARCHED

Class	Subclass	Date	Examiner
710	15,17,36,5 8,59	2/17/2006	DM
714	1,2,14	2/17/2006	DM
714	47,48	2/17/2006	DM

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East see attached	2/17/2006	DM
Inventor Search eDan	2/17/2006	DM
Databases: US Patents, US PGPUBS, USOCR, EPO, Derwent, IBM_TDB.	2/17/2006	DM